

Supporting information for In-situ electrochromic efficiency of nickel oxide thin film: origin of electrochemical process and electrochromic degradation

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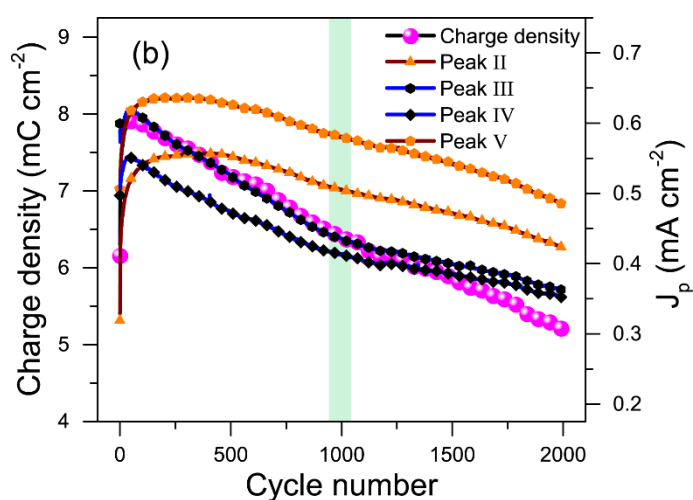


Figure S1. Evolutions of transferred charge density and current density at different peaks corresponding to CVs versus cycle number.